Applicant(s)/Patent Under Application/Control No. Reexamination 10/601,252 LEE ET AL. Notic of References Cited Examiner Art Unit Page 1 of 1 2186 Pierre-Michel Bataille **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY Chilton, Kendell A. Α US-6,751,703 06-2004 711/113 US-6,076,139 06-2000 Welker et al. 711/104 В С US-US-D US-E F US-US-G USн Ł US-J US-US-Κ US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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